

Counting Small Particles in Electron Microscopy Images — Proposal for Rules and Their Application in Practice

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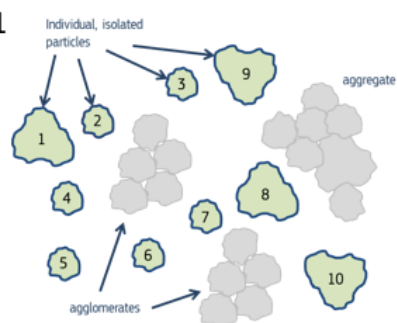
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Overview of Particle Counting Rules

CR1



Counting rule 1

only individual / non-touching particles are counted:

10 particles

CR2

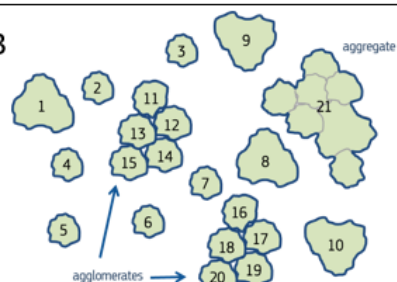


Counting rule 2

individual particles, aggregates and agglomerates are counted as one particle:

13 particles

CR3



Counting rule 3

Individual particles, constituent particles in agglomerates and aggregates are counted as one particle:

21 particles

CR4



Counting rule 4

Individual particles and constituent particles in agglomerates and in aggregates are counted as one particle

27 particles

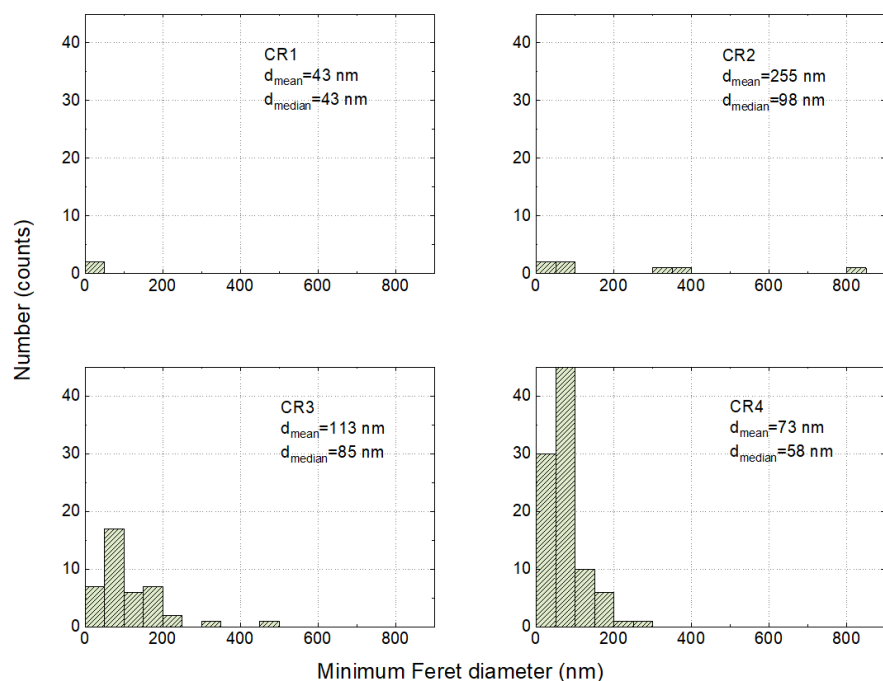


Figure S1. Minimum Feret Diameter of zinc oxide based on the application of the CR1 to CR4 to the TEM image in Fig. 6. As seen also from these graphs the number of particles counted varies significantly with counting rule applied as does the mean and median size of these particles.

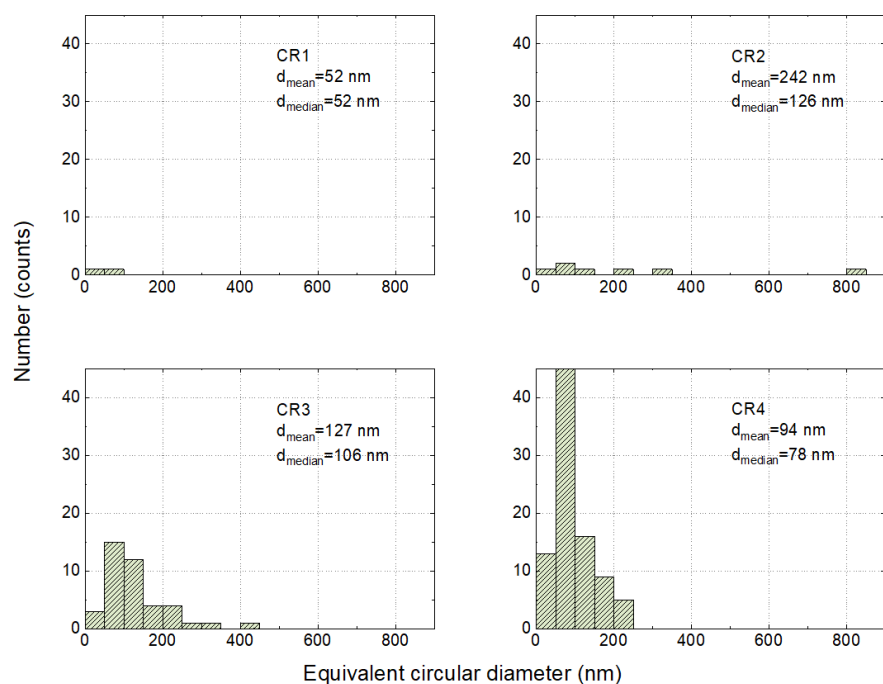


Figure S2. Equivalent circular diameter of zinc oxide as resulted after the application of the CR1 to CR4 to the TEM image in Fig. 6. As seen also from these graphs the number of particles counted varies significantly with counting rule applied as does the mean and median size of these particles.

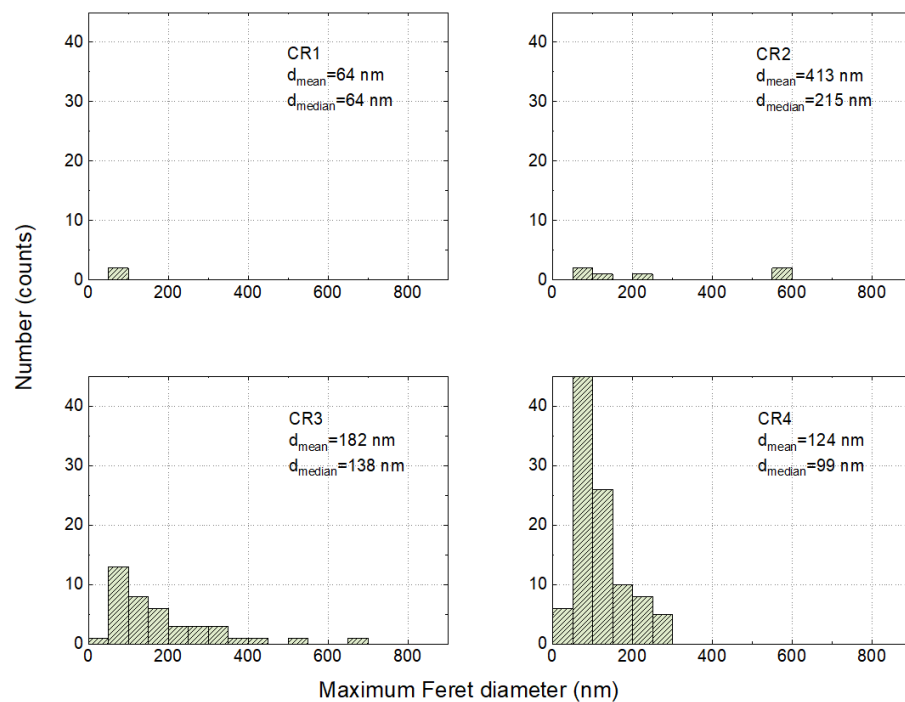


Figure S3. Maximum Feret Diameter of zinc oxide based on the application of the CR1 to CR4 to the TEM image in Fig. 6. As seen also from these graphs the number of particles counted varies significantly with counting rule applied as does the mean and median size of these particles.

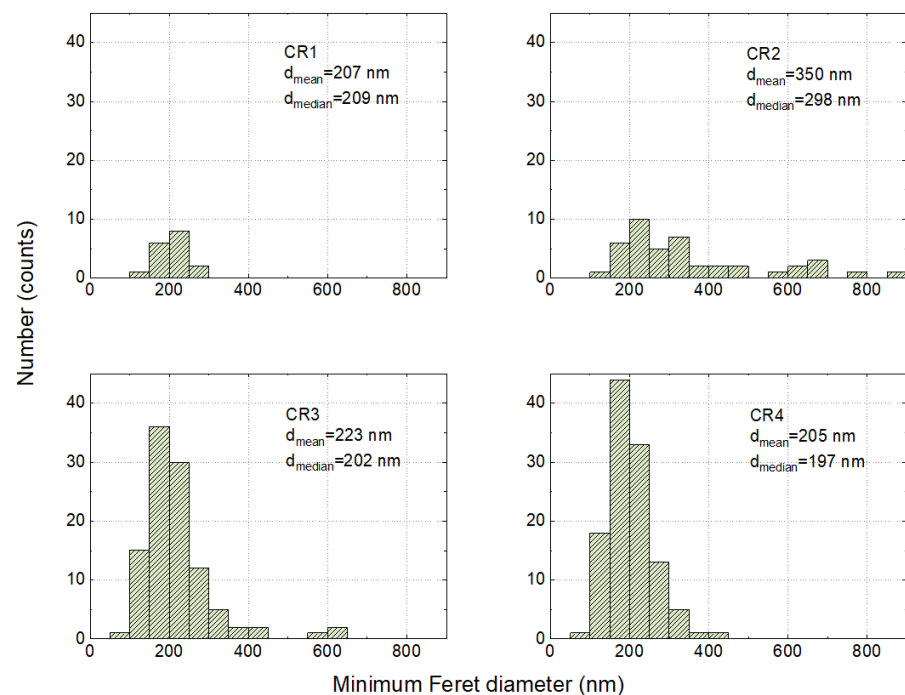


Figure S4. Minimum Feret Diameter of titanium oxide obtained after the application of the CR1 to CR4 to the TEM image in Fig. 7.

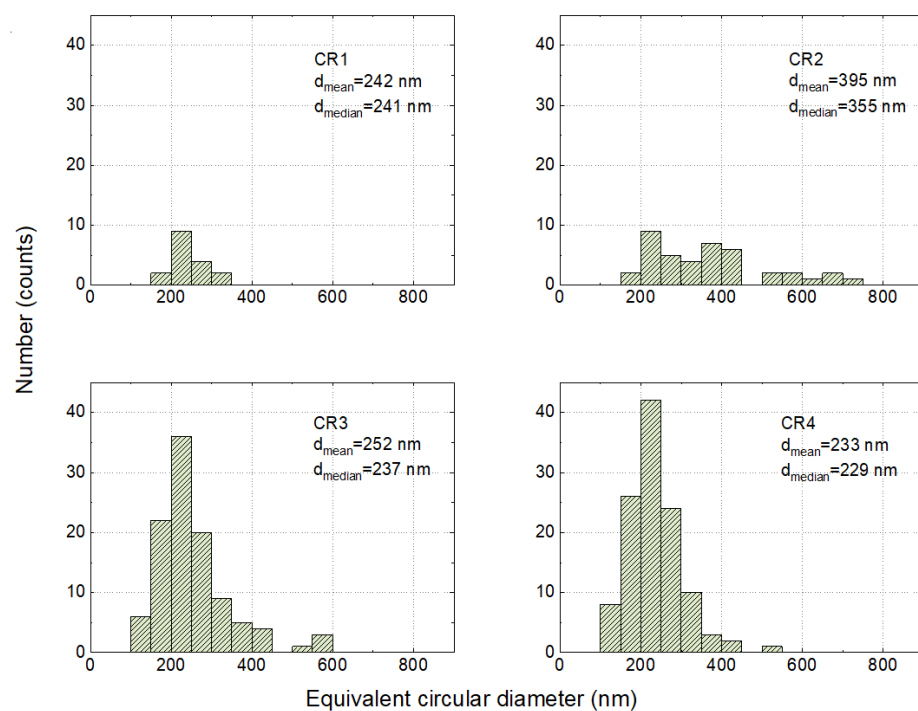


Figure S5. Equivalent spherical diameter of titanium oxide obtained after the application of the CR1 to CR4 to the TEM image in Fig. 7.

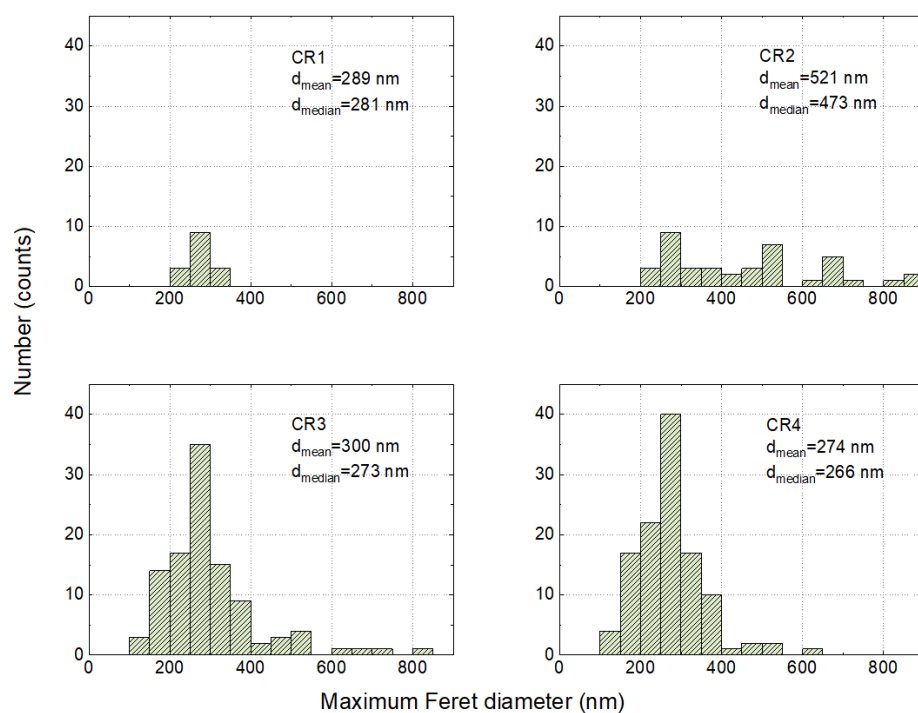


Figure S6. Maximum Feret Diameter of titanium oxide obtained after the application of the CR1 to CR4 to the TEM image in Fig. 7.

Table S1. compares descriptor values and results when applying the Counting Rules to the TEM micrograph (titanium dioxide) shown in Figure 7. The numbers are obtained assuming a lognormal distribution. See Figures S4–S6 for details of the corresponding particle size distributions.

d_{mean}; d_{median}; SD (nm)				
Counting rule	CR1	CR2	CR3	CR4
Descriptor				
Minimum Feret diameter	207; 209; ± 11	350; 298; ± 29	233; 202; ± 9	205; 197; ± 5
Equivalent circular diameter	242; 241; ± 10	395; 355; ± 30	252; 237; ± 9	233; 229; ± 6
Maximum Feret diameter	289; 281; ± 12	521; 473; ± 46	300; 273; ± 12	274; 266; ± 8

Information on image acquisition and used software

Image acquisition:

Titanium dioxide (Figure 7)

Instrument: ZEISS Gemini Supra 40

Electron beam voltage: 10 kV

Pixel size: 4.9 nm

Type of detector: SE InLens

Zinc oxide

Figure 6:

Instrument: JEOL JEM-2200FS

Electron beam voltage: 200 kV

Pixel size: 0.853 nm

Type of detector: Gatan CCD camera

Figure 8:

Instrument: ZEISS Gemini Supra 40

Electron beam voltage: 20 kV

Pixel size: 1.5 nm

Detector type: i) SE InLens and ii) conventional SE detector applied to the transmitted electrons via a dedicated sample holder (STEM-in-SEM)

Figure 9:

Instrument: ZEISS Gemini Supra 40

Electron beam voltage: 10 kV

Pixel size: 4.9 nm

Type of detector: SE InLens

Software:

ImageJ 2.1.0/1.53c

OriginPro2022